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OLIFF & BERRIDGE, PLC

ATTORNEYS AT LAW

Application Data Sheet**Applicant Information**

Applicant Authority type:: Inventor
 Primary Citizenship Country:: Japan
 Status:: Full Capacity
 Given Name:: Hideki
 Family Name:: SATO
 City of Residence:: Gunma
 Country of Residence:: Japan

Correspondence Information

Correspondence Customer Number:: 25944

Application Information

Application Type:: Regular
 Subject Matter:: Utility
 CD-ROM or CD-R:: None
 Title:: METHOD FOR EVALUATING CRYSTAL DEFECTS OF SILICON WAFER
 Attorney Docket Number:: 129546
 Suggested Drawing Figure:: 1
 Total Drawing Sheets:: 3
 Small Entity:: No

Representative Information

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Domestic Priority Information			
Application::	Continuity Type::	Parent Application::	Parent Filing Date::
This Application is a	National Phase of	PCT/JP2005/004294	03/11/05

Foreign Priority Information			
Country::	Application Number::	Filing Date::	Priority Claimed::
Japan	2004-095864	03/29/04	Yes
Assignee Information			
Assignee Name::		SHIN-ETSU HANDOTAI CO., LTD.	
Street of mailing address::		4-2, MARUNOUCHI 1-CHOME	
City of mailing address::		CHIYODA-KU	
State or Province of mailing address::		TOKYO	
Country of mailing address::		JAPAN	